Test Report issued under the responsibility of:





TEST PEPOPT IEC Story Low-voltage switchgear and controlgear - Part 2: Circuit-breakers				
Report Reference No Date of issue Total number of pages				
	. Shanghai Testing & Inspection Institute for Electrical Equipment Co.,Ltd. (STIEE)			
	505 Wu Ning Rd. Shanghai 200063, P.R. CHINA			
	Zhejiang Tengen Electrics Co., Ltd.			
	Sulv Industry Zone, Liushi, Yueqing, Zhejiang, P.R.China			
Test specification:				
	. IEC 60947-2:2006 (Fourth Edition) + A1: 2009 + A2: 2013			
Test procedure	. CB scheme			
Non-standard test method	N/A			
Test Report Form No	. IEC60947_2G			
Test Report Form(s) Originator	DEKRA Certification BV			
Master TRF	. Dated 2013-11			
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procedure shall be removed. This report is not valid as a CB	by non-IECEE members, the IECEE/IEC logo and the reference to the CB Scheme Test Report unless signed by an approved CB Testing Laboratory and appended to an NCB in accordance with IECEE 02.			
-	Moulded Case Circuit Breaker			
Trade Mark				
	Zhejiang Tengen Electrics Co., Ltd.			
	TGM1N-320L/M/H/R, TGM1N-250L/M/H/R			
	Ue: AC230/240V(2P), AC380/400/415V(3P,3P+N,4P),			
	AC660/690V(3P,3P+N,4P)			
	In: TGM1N-250L/M/H/R: 100A,125A,140A,150A,160A,170A,180A,200A,225A,250A;			
	TGM1N-320L/M/H/R:100A,125A,140A,150A,160A,170A,180A,			
	200A,225A,250A,270A,280A,300A,315A,320A;			

Testing procedure and testing location:				
CB Testing Laboratory:		Shanghai Testing & Inspection Institute for Electrical Equipment Co.,Ltd. (STIEE)		
Testing location/ address		505 Wu Ning Rd. Shanghai 200063, P.R. CHINA		
Tested by (name + function + signature):		Cui Tao/Engineer	· 作 魏 沃媛	
Approved by (name + funct signature)		Wei Qingyuan/Senior Engineer	魏沃媛	
Testing procedure: TMP		N/A		
Testing location/ address		N/A		
Tested by (name + signatur	·e):	N/A		
Approved by (name + signa	ature):	N/A		
Testing procedure: WMT		N/A		
Testing location/ address:		N/A		
Tested by (name + signatu	·e):	N/A		
Witnessed by (name + signature):		N/A		
Approved by (name + signa	ature):	N/A		
Testing procedure: SMT		N/A		
Testing location/ address:		N/A		
Tested by (name + signature):		N/A		
Approved by (name + signature):		N/A		
Supervised by (name + signature):		N/A		